transphorm

650V GaN FET PQFN Series

Description

The TP65H070L Series 650V, $72m\Omega$ Gallium Nitride (GaN) FET are normally-off devices. They combine state-of-the-art high voltage GaN HEMT and low voltage silicon MOSFET technologies—offering superior reliability and performance.

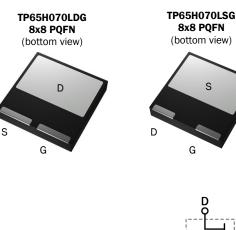
Transphorm GaN offers improved efficiency over silicon, through lower gate charge, lower crossover loss, and smaller reverse recovery charge.

Related Literature

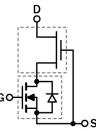
- AN0009: Recommended External Circuitry for GaN FETs
- AN0003: Printed Circuit Board Layout and Probing
- AN0010: Paralleling GaN FETs

Ordering Information

Part Number	Package	Package Configuration
TP65H070LDG	8 x 8mm PQFN	Drain
TP65H070LSG	8 x 8mm PQFN	Source







Cascode Schematic Symbol

Cascode Device Structure



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Features

- JEDEC qualified GaN technology
- Dynamic R_{DS(on)eff} production tested
- Robust design, defined by
 - Intrinsic lifetime tests
 - Wide gate safety margin
 - Transient over-voltage capability
- Very low QRR
- Reduced crossover loss
- · RoHS compliant and Halogen-free packaging

Benefits

- Improves efficiency/operation frequencies over Si
- Enables AC-DC bridgeless totem-pole PFC designs
 - Increased power density
 - Reduced system size and weight
 - Overall lower system cost
- · Easy to drive with commonly-used gate drivers
- GSD pin layout improves high speed design

Applications

- Datacom
- Broad industrial
- PV inverter
- Servo motor

Key Specifications

V _{DSS} (V)	650
V _{(TR)DSS} (V)	800
$R_{DS(on)eff}(m\Omega)$ max*	85
Q _{RR} (nC) typ	89
Q _G (nC) typ	9.3

* Dynamic on-resistance; see Figures 5 and 6

Absolute Maximum Ratings (Tc=25°C unless otherwise stated.)

Symbol	Parameter		Limit Value	Unit
V _{DSS}	Drain to source voltage $(T_J = -5)$	55°C to 150°C)	650	
V _{(TR)DSS}	Transient drain to source volta	ge a	800	V
V _{GSS}	Gate to source voltage		±20	
P _D	Maximum power dissipation @	Tc=25°C	96	W
	Continuous drain current @Tc=25°C b		25	А
lo	Continuous drain current @Tc=100°C b		16	А
I _{DM}	Pulsed drain current (pulse width: 10µs)		120	А
(di/dt) _{RDMC}	Reverse diode di/dt, repetitive °		1200	A/µs
(di/dt)rdmt	Reverse diode di/dt, transient	Reverse diode di/dt, transient ^d		A/µs
Tc	Operating temperature	Case	-55 to +150	°C
۲J	Operating temperature	Junction	-55 to +150	°C
Ts	Storage temperature		-55 to +150	°C
T _{SOLD}	Soldering peak temperature e	Soldering peak temperature ^e		°C

Notes:

a. In off-state, spike duty cycle D<0.01, spike duration <1 μ s

b. For increased stability at high current operation, see Circuit Implementation on page 3

c. Continuous switching operation

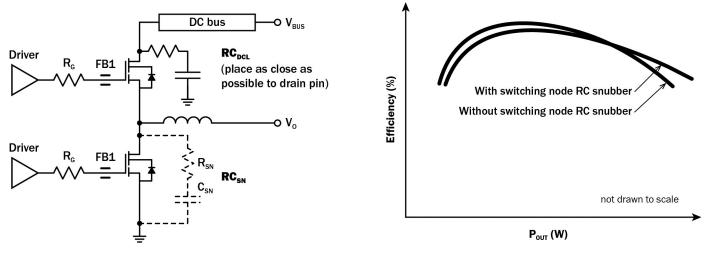
d. ≤300 pulses per second for a total duration ≤20 minutes

e. For 10 sec., 1.6mm from the case

Thermal Resistance

Symbol	Parameter	Maximum	Unit		
Rojc	Junction-to-case	1.3	°C/W		
Roja	Junction-to-ambient ^f	62	°C/W		
Notes: f. Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm ² copper area and 70µm thickness)					

Circuit Implementation



Simplified Half-bridge Schematic

Efficiency vs Output Power

Recommended gate drive: (0V, 12V) with $R_{G(tot)}$ = 50-70 Ω , where $R_{G(tot)}$ = R_{G} + R_{DRIVER}

Gate Ferrite Bead (FB1)	Required DC Link RC Snubber (RC_{DCL}) ^a	Recommended Switching Node RC Snubber (RC _{SN}) ^{b, c}
240ohm at 100MHz	[10nF + 10Ω] x 2	68pF + 15Ω

Notes:

a. RC_{DCL} should be placed as close as possible to the drain pin

b. A switching node RC snubber (C, R) is recommended for high switching currents (>70% of IRDMC1 or IRDMC2; see page 5 for IRDMC1 and IRDMC2)

c. I_{RDM} values can be increased by increasing R_{G} and C_{SN}

Electrical Parameter (T_J=25°C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions	
Forward Device Characteristics							
V _{(BL)DSS}	Drain-source voltage	650	_	_	V	V _{GS} =OV	
$V_{\text{GS}(\text{th})}$	Gate threshold voltage	3.3	4	4.8	V	V _{DS} =V _{GS} , I _D =0.7mA	
		-	72	85	mΩ	V _{GS} =10V, I _D =16A,T _J =25°C	
$R_{\text{DS(on)eff}}$	Drain-source on-resistance ^a	_	148	_		V _{GS} =10V, I _D =16A, T _J =150°C	
		-	3	30		V _{DS} =650V, V _{GS} =0V, T _J =25°C	
I _{DSS}	Drain-to-source leakage current	_	12	-	μA	V _{DS} =650V, V _{GS} =0V, T _J =150°C	
	Gate-to-source forward leakage current	-	-	100		V _{GS} =20V	
I _{GSS}	Gate-to-source reverse leakage current	_	_	-100	nA	V _{GS} =-20V	
CISS	Input capacitance	-	600	-			
Coss	Output capacitance	-	88	-	pF	V _{GS} =0V, V _{DS} =400V, <i>f</i> =1MHz	
C _{RSS}	Reverse transfer capacitance	-	4.5	-			
$C_{O(er)}$	Output capacitance, energy related b	-	131	-	pF		
C _{O(tr)}	Output capacitance, time related °	-	217	_	рг	V_{GS} =0V, V_{DS} =0V to 400V	
Q_{G}	Total gate charge	-	9.3	_		V_{DS} =400V, V_{GS} =0V to 10V, I_{D} =16A	
Q _{GS}	Gate-source charge	-	3.5	-	nC		
\mathbf{Q}_{GD}	Gate-drain charge	-	2.3	-			
Qoss	Output charge	_	85	-	nC	V_{GS} =0V, V_{DS} =0V to 400V	
t _{D(on)}	Turn-on delay	-	29	_			
t _R	Rise time	-	7.5	_	ns	V_{DS} =400V, V_{GS} =0V to 12V, I_D=16A, R_G=50\Omega,	
$t_{\text{D(off)}}$	Turn-off delay	-	45	_	115	$Z_{FB} = 240\Omega$ at 100MHz	
t _F	Fall time	_	8.2	_			

Notes:

a. Dynamic on-resistance; see Figures 5 and 6 for test circuit and conditions

b. Equivalent capacitance to give same stored energy as V_{DS} rises from 0V to 400V

c. Equivalent capacitance to give same charging time as V_{DS} rises from OV to 400V

Electrical Parameters (T_=25°C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions
Reverse Dev	ice Characteristics					
ls	Reverse current	_	_	16	A	V_{GS} =0V, T _C =100°C, ≤25% duty cycle
M		_	1.8	-		V _{GS} =0V, I _S =16A
V_{SD}	Reverse voltage ^a	_	1.3	_	V	V _{GS} =0V, I _S =8A
t _{RR}	Reverse recovery time	_	33	-	ns	I _S =16A, V _{DD} =400V,
Q_{RR}	Reverse recovery charge	_	89	_	nC	di/dt=1000A/ms
(di/dt) _{RDMC}	Reverse diode di/dt, repetitive b	_	_	1200	A/µs	
IRDMC1	Reverse diode switching current, repeti- tive (dc) ^{c, e}	_	_	18	A	Circuit implementation and parameters on page 3
I _{RDMC2}	Reverse diode switching current, repeti- tive (ac) ^{c, e}	_	_	23	A	Circuit implementation and parameters on page 3
(di/dt) _{RDMT}	Reverse diode di/dt, transient d	_	_	2600	A∕µs	
I _{RDMT}	Reverse diode switching current, transient d,e	_	_	28	A	Circuit implementation and parameters on page 3

Notes:

a. Includes dynamic $R_{DS(on)}$ effect

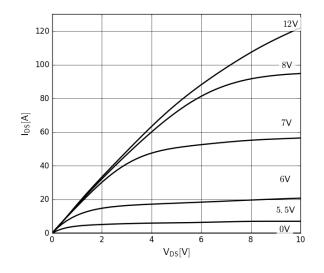
b. Continuous switching operation

c. Definitions: dc = dc-to-dc converter topologies; ac = inverter and PFC topologies, 50-60Hz line frequency

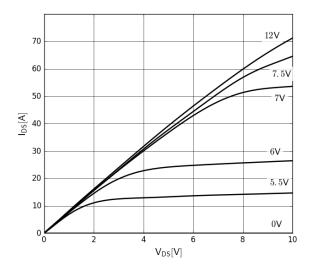
d. \leq 300 pulses per second for a total duration \leq 20 minutes

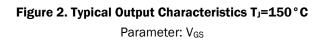
e. I_{RDM} values can be increased by increasing R_{G} and C_{SN} on page 3

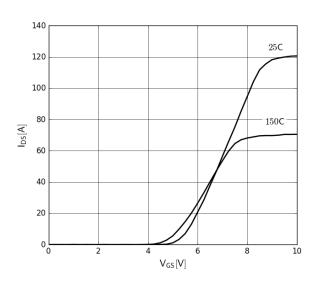
Typical Characteristics (Tc=25 °C unless otherwise stated)

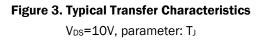


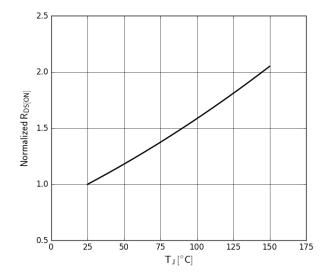


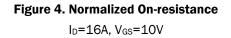












Typical Characteristics (Tc=25 °C unless otherwise stated)

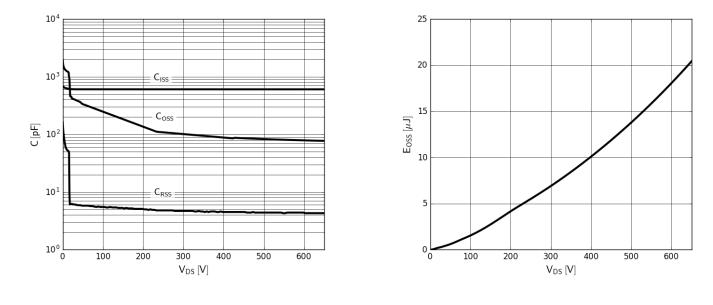
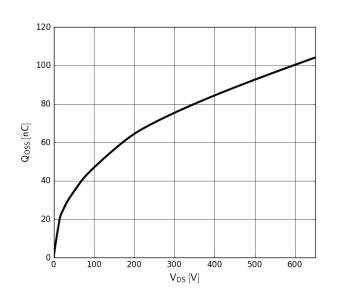
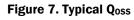


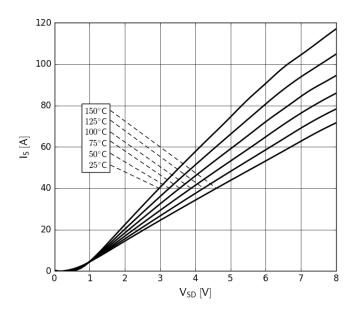
Figure 5. Typical Capacitance

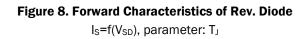
 V_{GS} =0V, f=1MHz

Figure 6. Typical Coss Stored Energy









Typical Characteristics (Tc=25 $^{\circ}$ C unless otherwise stated)

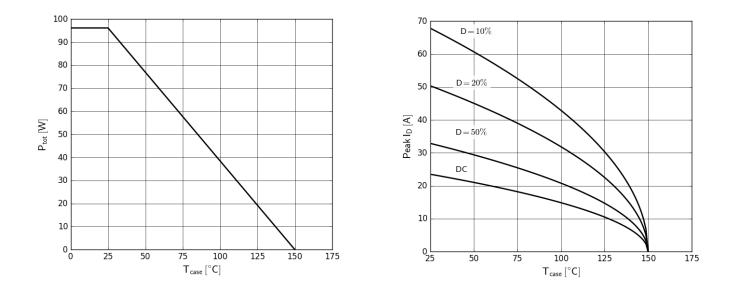


Figure 9. Power Dissipation

Figure 10. Current Derating Pulse width $\leq 10\mu s$, $V_{GS} \geq 10V$

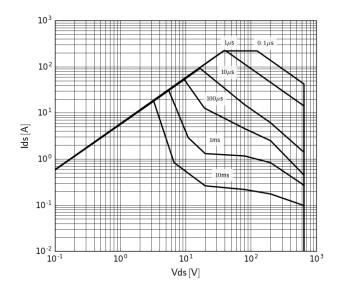


Figure 11. Safe Operating Area $T_{\text{C}}\text{=}25\,^{\circ}\text{C}$

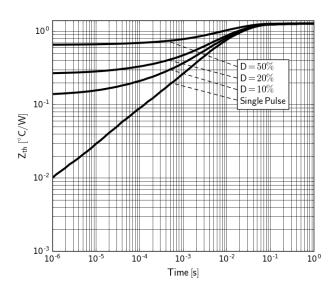


Figure 12. Transient Thermal Resistance

Test Circuits and Waveforms

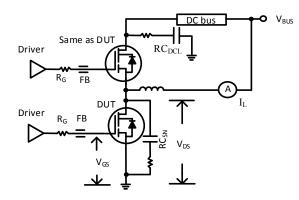


Figure 13. Switching Time Test Circuit (see circuit implementation on page 3 for methods to ensure clean switching)

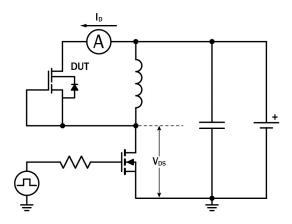


Figure 15. Diode Characteristics Test Circuit

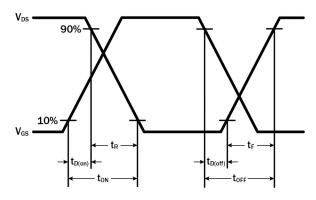


Figure 14. Switching Time Waveform

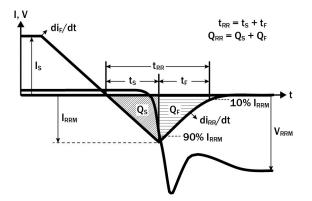
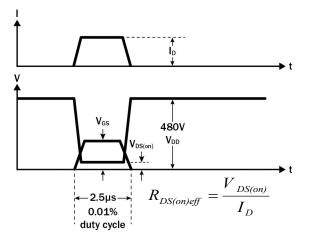


Figure 16. Diode Recovery Waveform





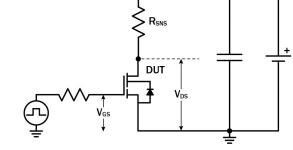


Figure 17. Dynamic RDS(on)eff Test Circuit

Design Considerations

The fast switching of GaN devices reduces current-voltage crossover losses and enables high frequency operation while simultaneously achieving high efficiency. However, taking full advantage of the fast switching characteristics of GaN switches requires adherence to specific PCB layout guidelines and probing techniques.

Before evaluating Transphorm GaN devices, see application note <u>Printed Circuit Board Layout and Probing for GaN Power</u> <u>Switches</u>. The table below provides some practical rules that should be followed during the evaluation.

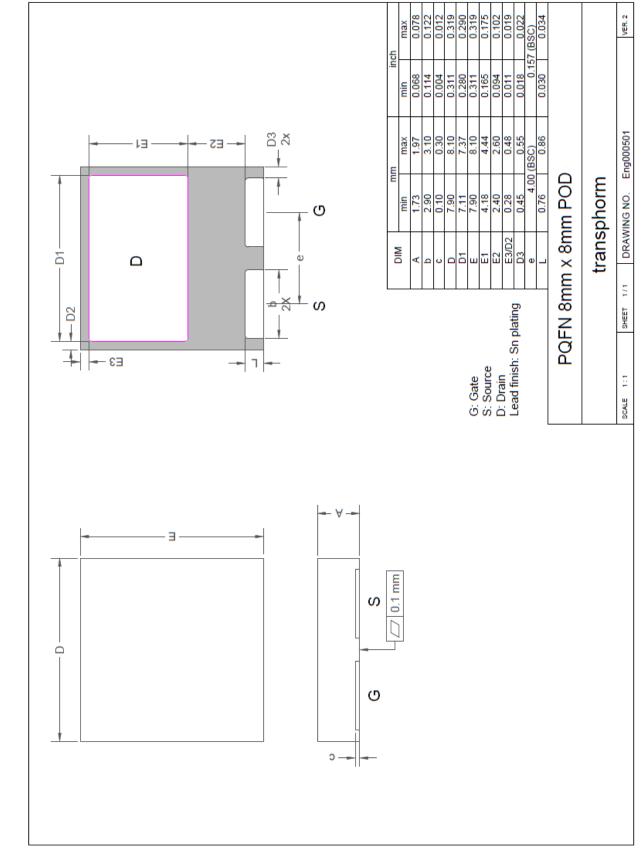
When Evaluating Transphorm GaN Devices:

DO	DO NOT
Minimize circuit inductance by keeping traces short, both in the drive and power loop	Twist the pins of TO-220 or TO-247 to accommodate GDS board layout
Minimize lead length of TO-220 and TO-247 package when mounting to the PCB	Use long traces in drive circuit, long lead length of the devices
Use shortest sense loop for probing; attach the probe and its ground connection directly to the test points	Use differential mode probe or probe ground clip with long wire
See AN0003: Printed Circuit Board Layout and Probing	

GaN Design Resources

The complete technical library of GaN design tools can be found at transphormusa.com/design:

- Reference designs
- Evaluation kits
- Application notes
- Design guides
- Simulation models
- Technical papers and presentations

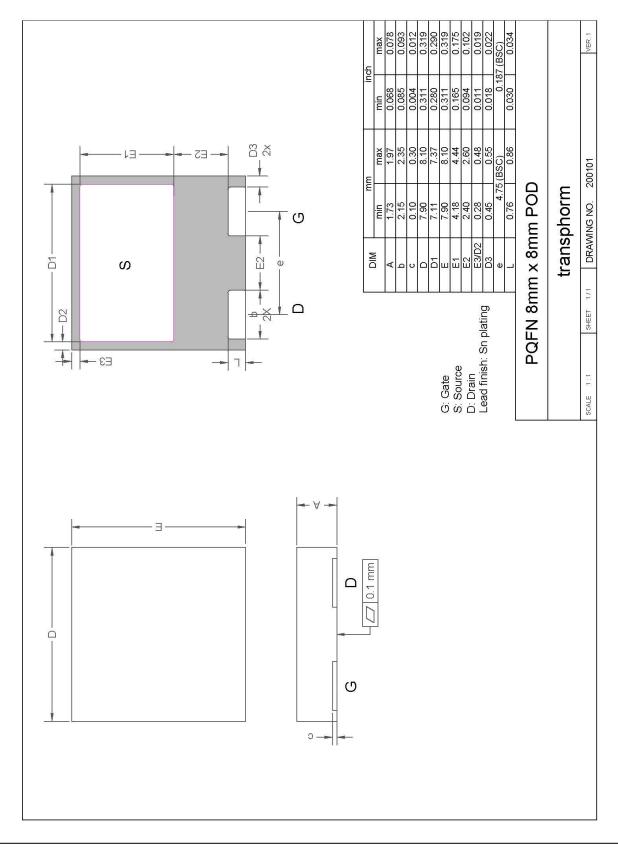


8x8 PQFN (LDG) Package

May 15, 2019 tp65h070l.1

Mechanical

transphormusa.com



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Revision History

Version	Date	Change(s)	
0	2/17/2019	Preliminary Datasheet	
1	5/15/2019	Datasheet Complete	



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